

2A, 600V N-CHANNEL MOSFET

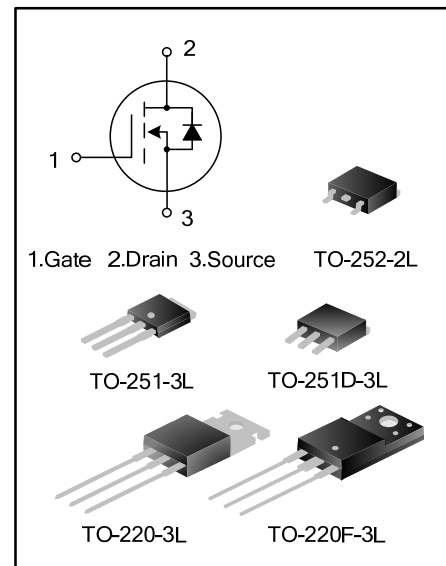
GENERAL DESCRIPTION

SVD2N60M/F/T/D is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary S-Rin™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

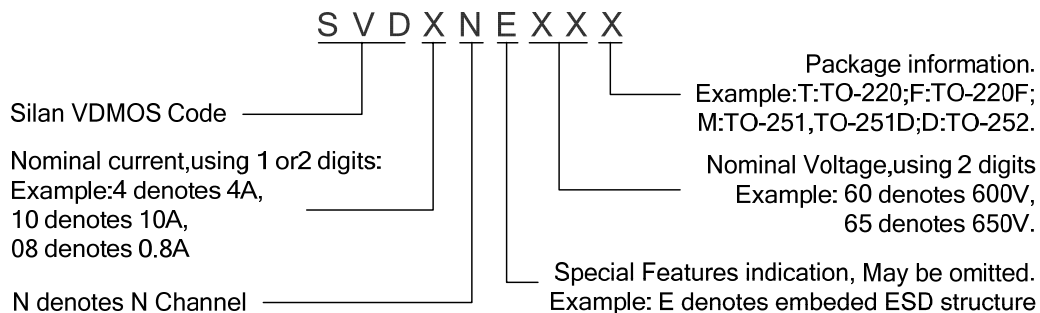
These devices are widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- * 2A,600V,RDS(on)(typ.)=4.0Ω@VGS=10V
- * Low gate charge
- * Low Crss
- * Fast switching
- * Improved dv/dt capability



NOMENCLATURE



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SVD2N60M	TO-251-3L	SVD2N60M	Pb free	Tube
SVD2N60M	TO-251D-3L	SVD2N60M	Pb free	Tube
SVD2N60F	TO-220F-3L	SVD2N60F	Pb free	Tube
SVD2N60T	TO-220-3L	SVD2N60T	Pb free	Tube
SVD2N60D	TO-252-2L	SVD2N60D	Pb free	Tube
SVD2N60DTR	TO-252-2L	SVD2N60D	Pb free	Tape & Reel

ABSOLUTE MAXIMUM RATINGS (Tc=25°C unless otherwise noted)

Characteristics	Symbol	Rating			Unit
		SVD2N60M/D	SVD2N60T	SVD2N60F	
Drain-Source Voltage	VDS	600			V
Gate-Source Voltage	VGS	±30			V
Drain Current	ID	2.0			A
Drain Current Pulsed	IDM	8.0			A
Power Dissipation(Tc=25°C) -Derate above 25°C	PD	34	44	23	W
		0.27	0.35	0.18	W/°C
Single Pulsed Avalanche Energy (Note 1)	EAS	118			mJ
Operation Junction Temperature	TJ	-55~+150			°C
Storage Temperature	Tstg	-55~+150			°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Rating			Unit
		SVD2N60M/D	SVD2N60T	SVD2N60F	
Thermal Resistance, Junction-to-Case	RθJC	3.7	2.86	5.56	°C/W
Thermal Resistance, Junction-to-Ambient	RθJA	110	62.5	120	°C/W

ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise noted)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BVDSS	VGS=0V, ID=250μA	600	--	--	V
Drain-Source Leakage Current	IDSS	VDS=600V, VGS=0V	--	--	1.0	μA
Gate-Source Leakage Current	IGSS	VGS=±30V, VDS=0V	--	--	±100	nA
Gate Threshold Voltage	VGS(th)	VGS= VDS, ID=250μA	2.0	--	4.0	V
Static Drain- Source On State Resistance	RDS(on)	VGS=10V, ID=1.0A	--	4.0	4.6	Ω
Input Capacitance	Ciss	VDS=25V, VGS=0V, f=1.0MHZ	--	320	380	pF
Output Capacitance	Coss		--	30	45	
Reverse Transfer Capacitance	Crss		--	3	5.6	
Turn-on Delay Time	td(on)	VDD=300V, ID=2.0A, RG=25Ω (Note 2,3)	--	13	30	ns
Turn-on Rise Time	tr		--	12	60	
Turn-off Delay Time	td(off)		--	73	100	
Turn-off Fall Time	tf		--	14.3	70	
Total Gate Charge	Qg	VDS=480V, ID=2.0A, VGS=10V (Note 2,3)	--	9.3	13	nC
Gate-Source Charge	Qgs		--	2.0	--	
Gate-Drain Charge	Qgd		--	3.3	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	IS	Integral Reverse P-N	--	--	2.0	A
Pulsed Source Current	ISM	Junction Diode in the MOSFET	--	--	8.0	
Diode Forward Voltage	VSD	IS=2.0A, VGS=0V	--	--	1.4	V
Reverse Recovery Time	Trr	IS=2.0A, VGS=0V,	--	230	--	ns
Reverse Recovery Charge	Qrr	dIF/dt=100A/μS	--	1.0	--	μC

Notes:

1. L=30mH, IAS=2.58A, VDD=123V, RG=25Ω, starting TJ=25°C;
2. Pulse Test: Pulse width ≤300μs, Duty cycle ≤2%;
3. Essentially independent of operating temperature.

TYPICAL CHARACTERISTICS

Figure 1. On-Region Characteristics

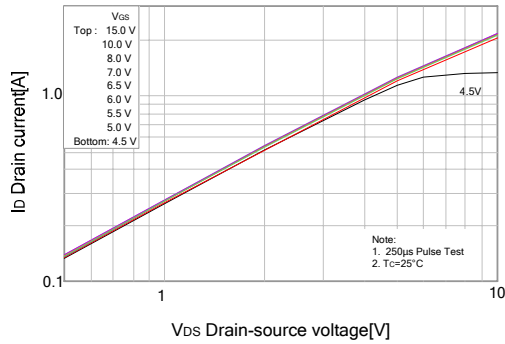


Figure 2. Transfer Characteristics

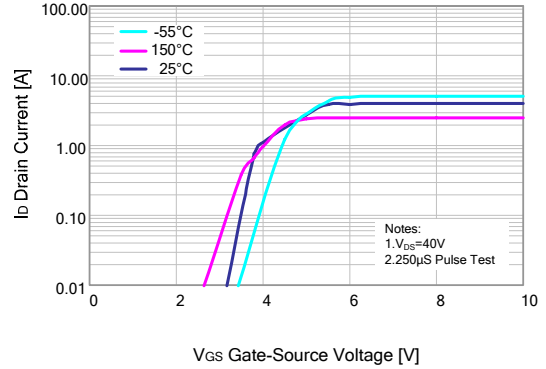


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

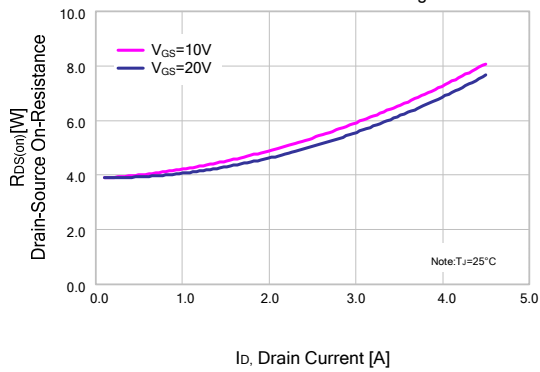


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

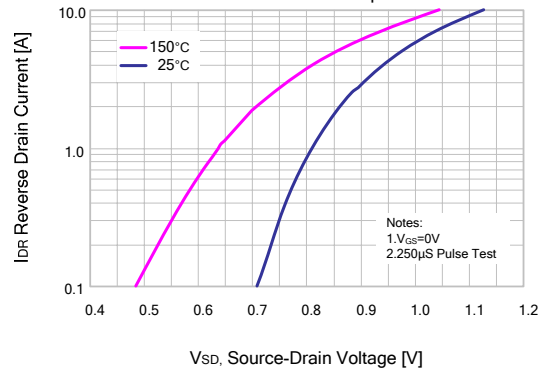


Figure 5. Capacitance Characteristics

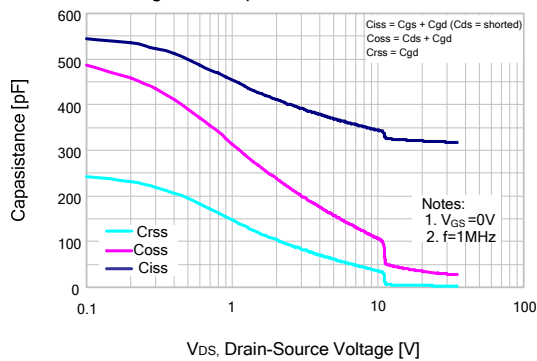
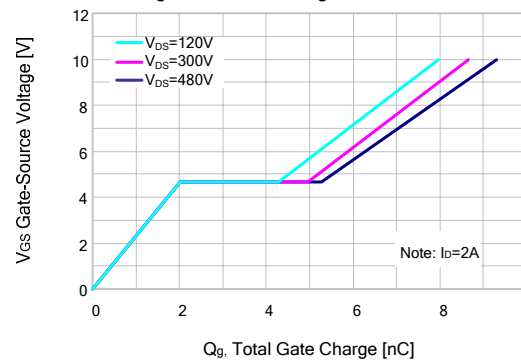


Figure 6. Gate Charge Characteristics



TYPICAL CHARACTERISTICS (continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

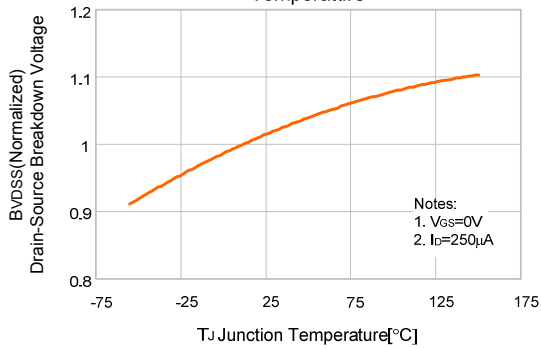


Figure 8. On-resistance Variation vs Temperature

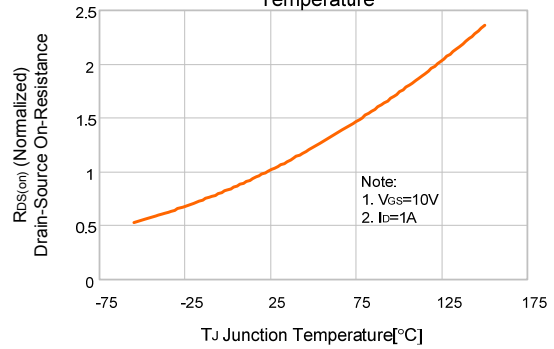


Figure 9-1. Max. Safe Operating Area(SVD2N60M/D)

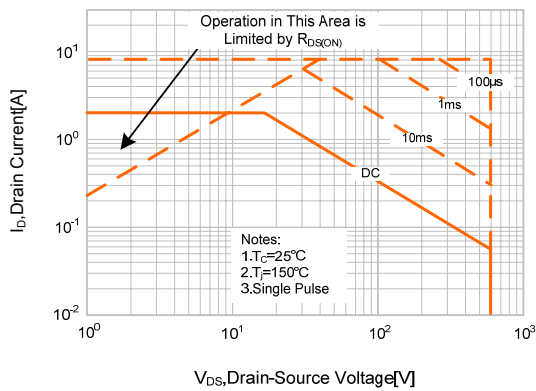


Figure 9-2. Max. Safe Operating Area(SVD2N60T)

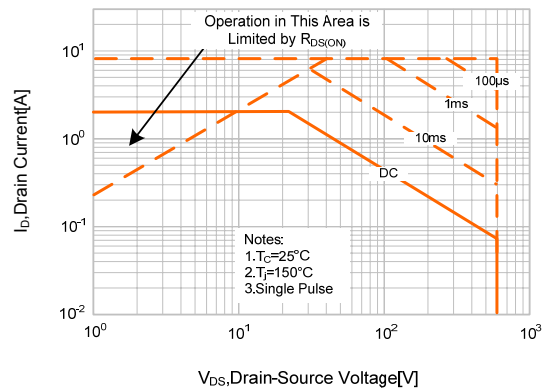


Figure 9-3. Max. Safe Operating Area(SVD2N60F)

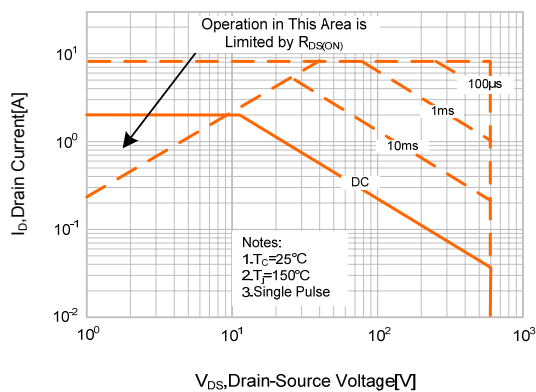
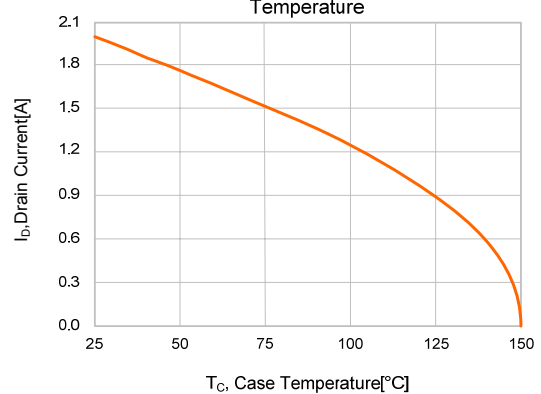
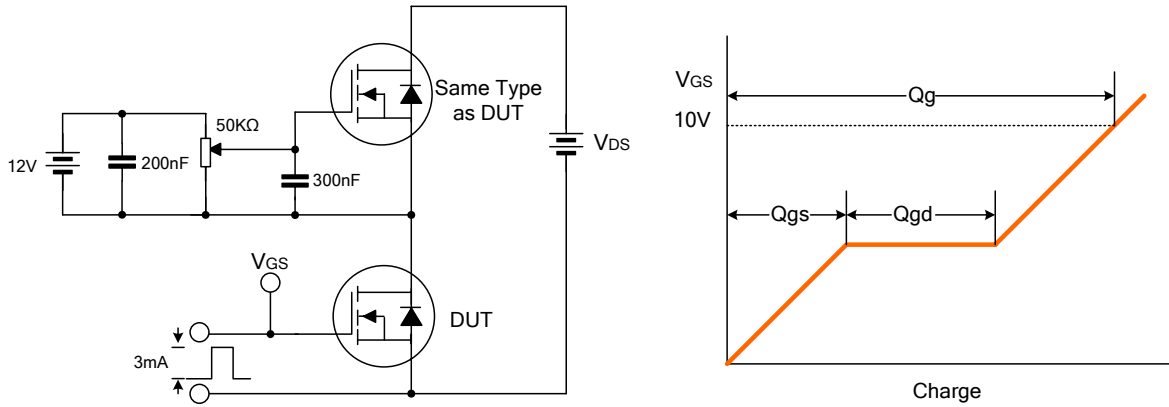


Figure 10. Maximum Drain Current vs. Case Temperature

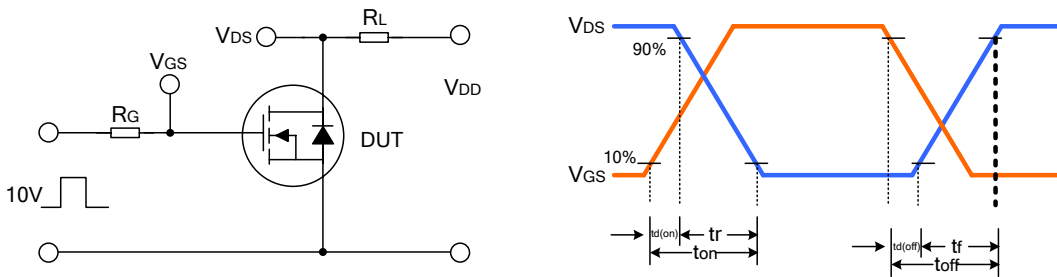


TYPICAL TEST CIRCUIT

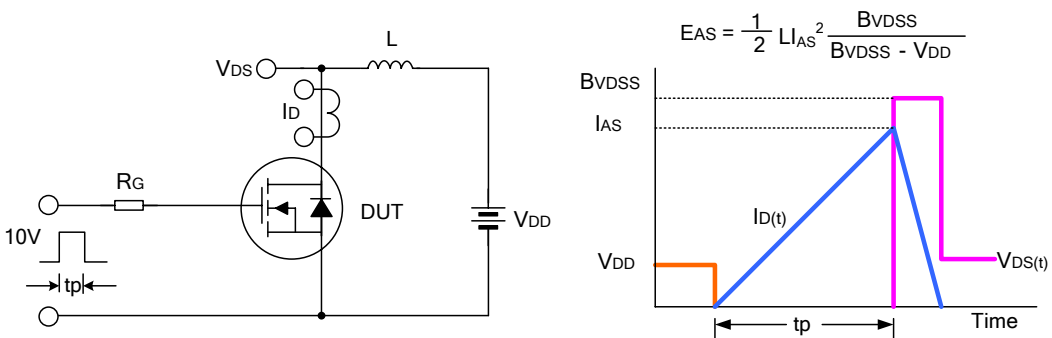
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



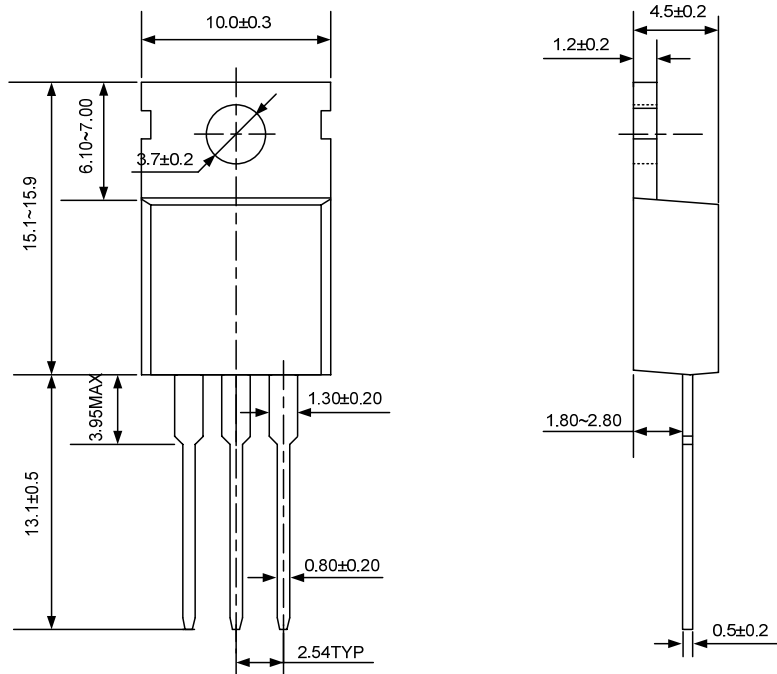
Unclamped Inductive Switching Test Circuit & Waveform



PACKAGE OUTLINE

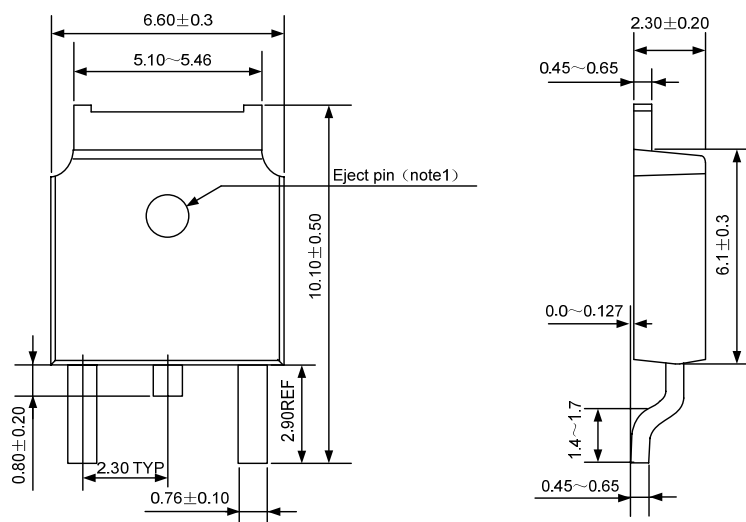
TO-220-3L

UNIT: mm



TO-252-2L

UNIT: mm

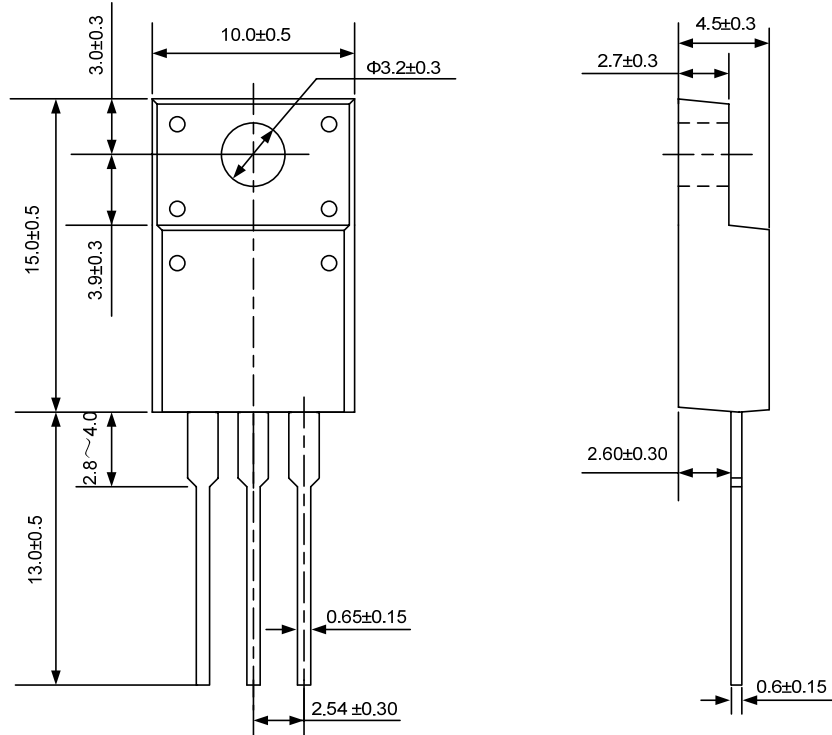


NOTE1 : There are two conditions for this position:has an eject pin or has no eject pin.

PACKAGE OUTLINE (continued)

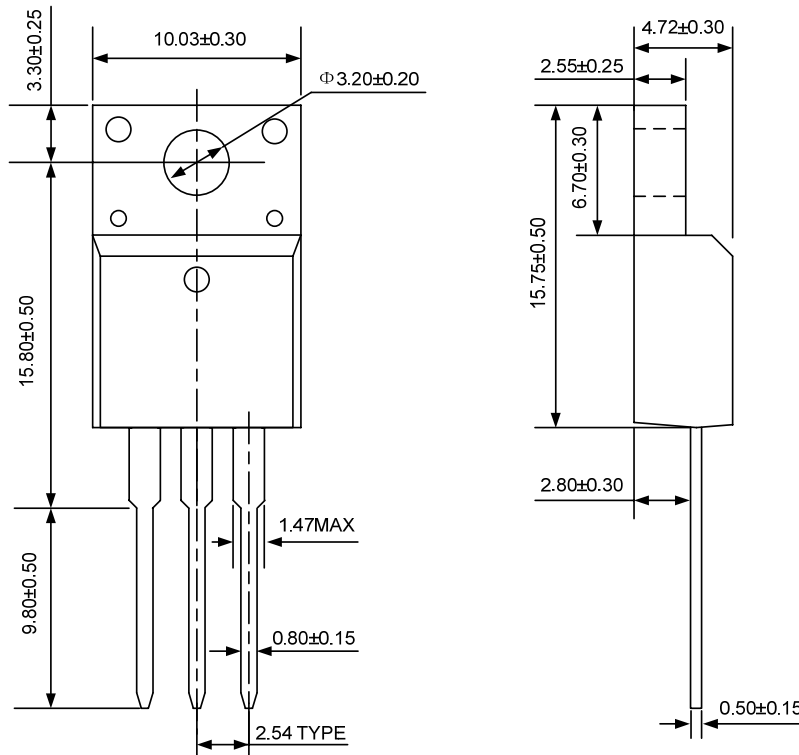
TO-220F-3L(One)

UNIT: mm



TO-220F-3L(Two)

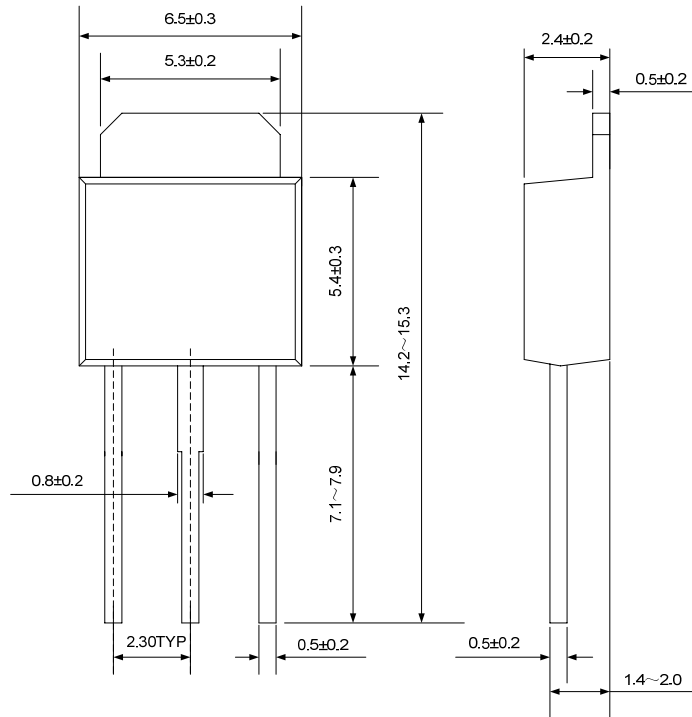
UNIT: mm



PACKAGE OUTLINE (continued)

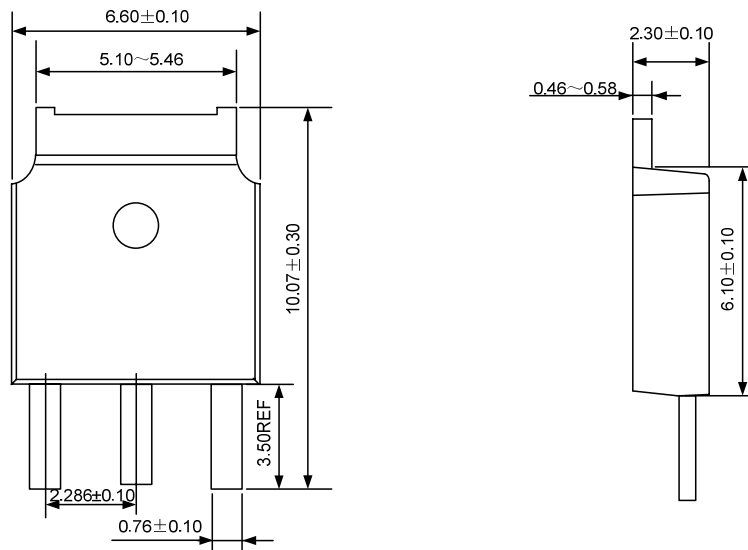
TO-251-3L

UNIT: mm



TO-251D-3L

UNIT: mm





Disclaimer:

- Silan reserves the right to make changes to the information herein for the improvement of the design and performance without further notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- All semiconductor products malfunction or fail with some probability under special conditions. When using Silan products in system design or complete machine manufacturing, it is the responsibility of the buyer to comply with the safety standards strictly and take essential measures to avoid situations in which a malfunction or failure of such Silan products could cause loss of body injury or damage to property.
- Silan will supply the best possible product for customers!

ATTACHMENT

Revision History

Date	REV	Description	Page
2010.05.13	1.0	Original	
2010.08.20	1.1	Modify "ABSOLUTE MAXIMUM RATINGS", "THERMAL CHARACTERISTICS"; Add SOA & ID-TC	
2010.10.18	1.2	Modify "TYPICAL CHARACTERISTICS", "PACKAGE OUTLINE", the template of Datasheet	
2011.06.28	1.3	Modify the "PACKAGE OUTLINE(continued)"	8
		Add the package of TO-251D-3L	9